

## RHT1490J

The RHT1490J is a high frequency Stratum 3 TCXO specifically designed to meet telecommunications grade stabilities at high frequencies with low phase jitter. This product's frequency output enables lower system jitter, allowing communication system architects to optimise noise budget and performance. Having the optimal balance between close-in phase noise and the noise floor, makes it suitable to be the single reference clock used for both network and air interface requirements. Its ultra-low noise floor performance helps to achieve very low system clock RMS jitter levels need in high speed interfaces (40G/100G).

Comfortably achieving Stratum 3 grade stability, its CMOS output generates < 200 fs of RMS phase jitter (12 kHz – 20 MHz), in a 14 x 9 mm SMD package. An ideal reference clock solution for SyncE and Packet clock requirements (ITU-T G.813, G.8262, G.82673.2 and G8273.3), it also works with both discrete and integrated IEEE 1588 solutions – providing excellent medium term stability for low loop bandwidth applications.

### Features

- Telecommunications grade Stratum 3 stability
- Low jitter < 200 fs (12 kHz to 20 MHz)
- High frequency options from 50 – 200 MHz
- Inherent airflow resistance

### Applications

- Stratum 3 equipment
- Carrier Ethernet/Microwave
- Telecom PLLs
- ITU-T G.813, G.8262, G.82673.2 and G8273.3
- Radio Head Clock Recovery (IEEE 1588/SyncE)
- 10/25/40/100G Ethernet

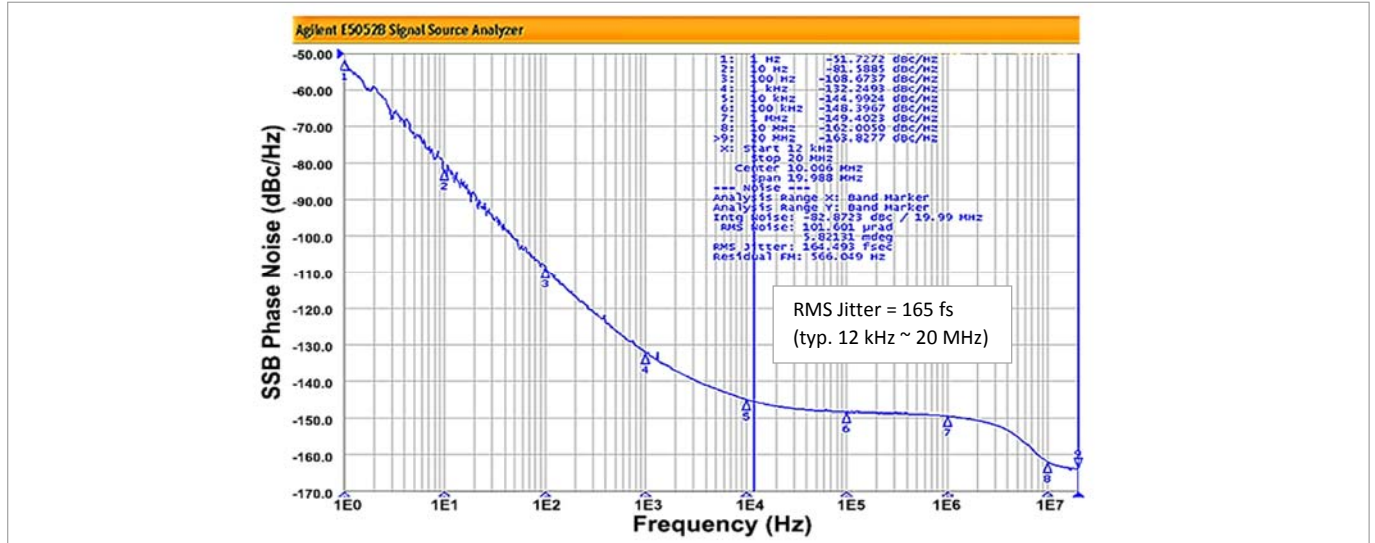
14.4 x 9.2 x 4.7 mm



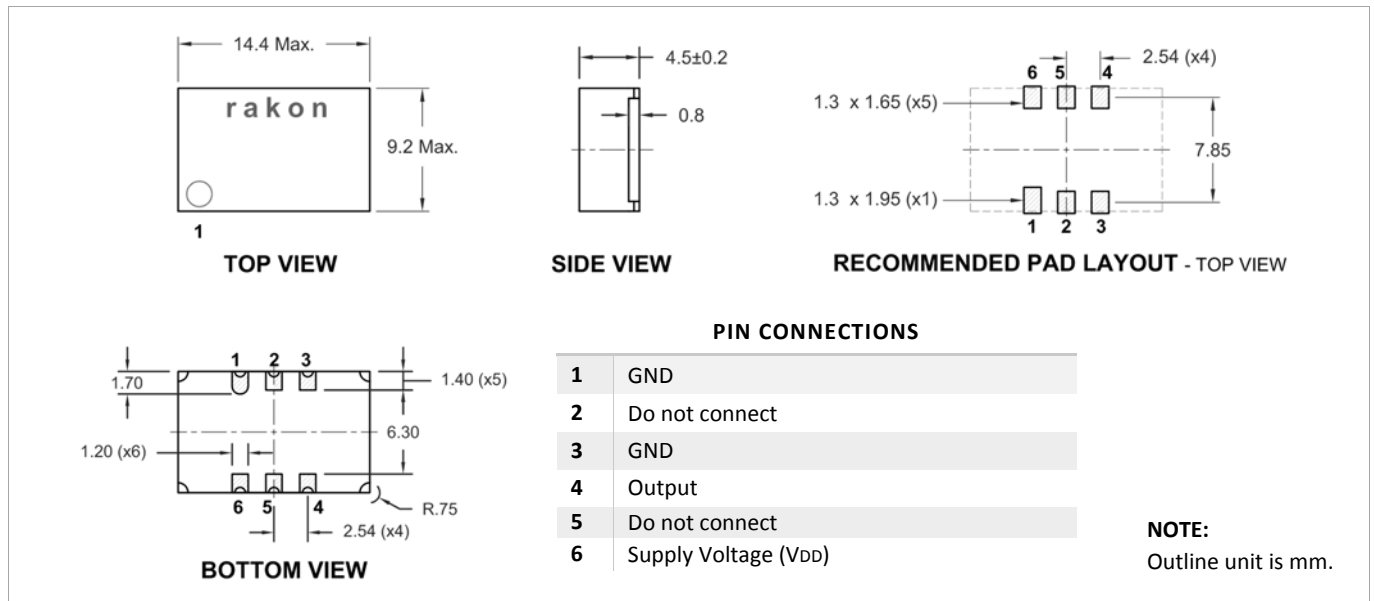
### Standard Specifications

Parameter	Min.	Typ.	Max.	Unit	Test Condition / Description
Nominal frequency		50 – 200		MHz	Standard frequencies: 98.304, 100, 125, and 156.25 MHz
Frequency calibration			±1.0	ppm	Initial accuracy at 25°C ±2°C
Reflow shift			±1.0	ppm	Pre to post reflow ΔF (measured ≥ 60 minutes after reflow)
Operating temperature range	-40		85	°C	
Frequency stability over temperature			± 0.28	ppm	The default reference for holdover stability, variable temperature is (F <sub>MAX</sub> + F <sub>MIN</sub> )/2
Free-run accuracy			±4.6	ppm	Including frequency calibration, temperature, supply voltage & load changes and 20 years ageing
Supply voltage stability			±0.1	ppm	±5% variation, reference to frequency at 3.3 V
Load sensitivity			±0.1	ppm	±5 pF variation, reference to frequency at 5 pF
Long term stability (ageing at 40°C)			±10 ±2.5	ppb ppm	Per day, after 10 days of continuous operation 20 years
Acceleration sensitivity		2		ppb/g	Gamma vector, 3 axes, 30 – 1500 Hz
Start-up time			1	ms	90% amplitude
Supply voltage (V <sub>DD</sub> )		3.3 2.5		V	±5%, Fn = 50 – 160 MHz ±5%, Fn = 160 – 200 MHz
Supply current			14	mA	5 pF//1 kΩ, 100 MHz
Oscillator output - CMOS					
Output voltage level low (V <sub>OL</sub> )			20%	V <sub>DD</sub>	With capacitive load of 5pF, 100 MHz
Output voltage level high (V <sub>OH</sub> )	80%			V <sub>DD</sub>	With capacitive load of 5pF, 100 MHz
Rise time		1.2	1.5	ns	Measured 20% to 80% V <sub>DD</sub> , 5 pF load, 100 MHz
Fall time		1.2	1.5	ns	Measured 80% to 20% V <sub>DD</sub> , 5 pF load, 100 MHz
Duty cycle	45		55	%	Measured at 50% V <sub>DD</sub> trigger level, 100 MHz
Load		5		pF	

## SSB Phase Noise – 98.304 MHz RHT1490 TCXO (Typical value at 25°C, CMOS output)



## Model Outline, Recommended Pad Layout



## Test Circuit

